


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	09/807,158	DIEHL ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Thanh X. Luu	2878	

SEARCHED			
Class	Subclass	Date	Examiner
	Searched to date	11/04	TXL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Same as	above	11/04	TXL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR